



# Outline

1. My Background
2. Research field of interest and study activities
3. Research activity
  1. Embedded Artificial Intelligence
  2. Cyber-physical Attacks on Embedded Devices
4. Future activities

# My background

- MSc degree: Electronic Engineering (University of Naples “Federico II”)
- Research group/laboratory: ARHeMLab
- PhD start date: 01/01/2022
- Scholarship type: MUR PON – Green action
- Industry period: 12 months, STMicroelectronics, Marcianise, Italy
- Abroad period: 6 months, CSLab, STMicroelectronics Rousset, France (by remote)

# Research field of interest

- Metrological approach for cybersecurity in Smart Industry



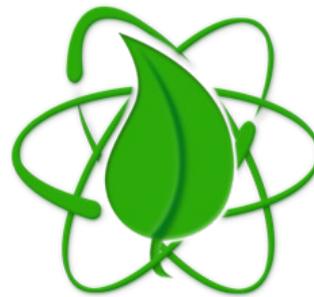
Smart Home



Smart Agriculture



Smart Building



Smart Vehicle



Smart Factory



Smart Health

# Research field of interest



## PRODUCTION OF DATA

Transducers, Edge Technologies, Connection Standards, Connection Protocols



## ELABORATION OF DATA

Cloud computing, Edge Computing, Tiny Computing



## SUSTAINABILITY

Energy Impact, Disposal



## SECURITY

Data transmission, Cryptography, Denial of Service, Cyberattacks

# Summary of study activities

1

## **EMBEDDED ARTIFICIAL INTELLIGENCE**

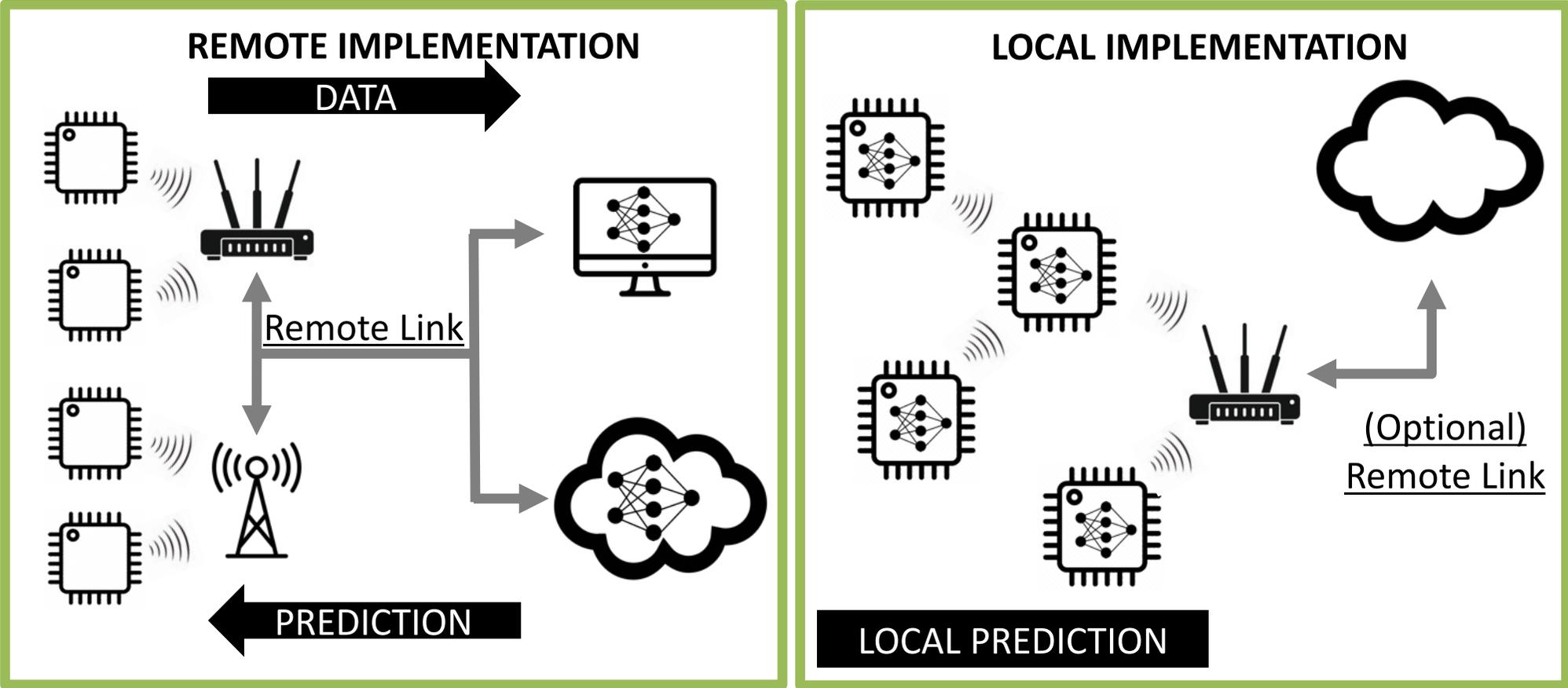
- Time and Energy performance metrics
- Optimization techniques
- Assessment measure setups
- Uncertainty estimation

2

## **METROLOGY FOR CYBERATTACKS ON EMBEDDED DEVICES**

- Side-Channel Attacks
- Machine learning techniques applied to Side-Channel
- Uncertainty estimation on such attacks

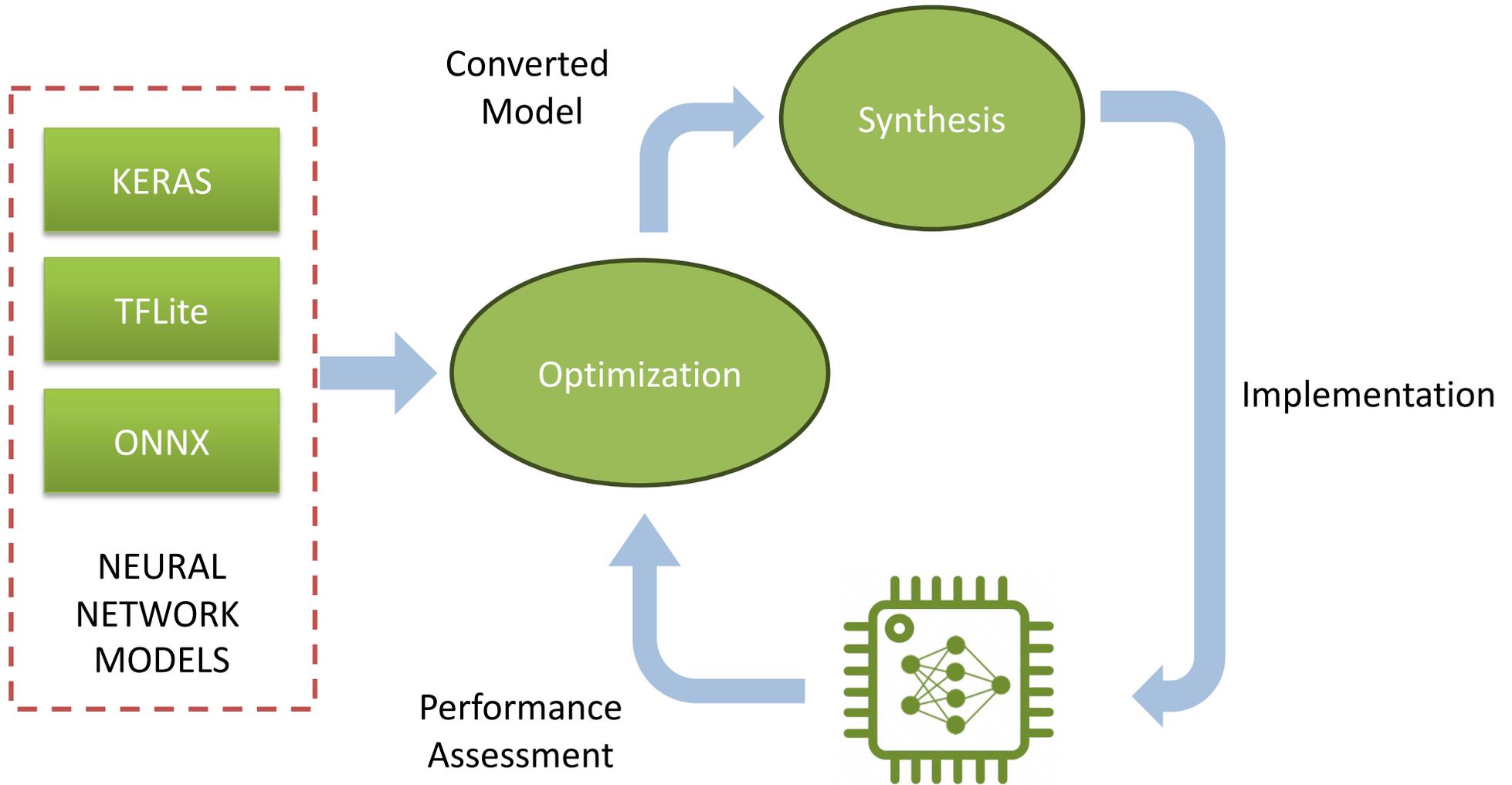
# Embedded AI



# Embedded AI

- Advantages
  - **Offline Elaboration:** A denial of remote service or no active network does not affect the functionality of the device
  - **Security & Safety:** Data stays on device and cannot be stolen or changed in transmission
  - **Economical & Green:** Remote computing is not needed
- Disadvantages
  - **Hardware:** Small amount of hardware resources and battery supplied
  - **Overheating**
- Challenges
  - **Timing Performance**
  - **Power Performance**

# Embedded AI



# Embedded AI – MLCommons

**MLCommons** is an Artificial Intelligence engineering consortium, built on a philosophy of open collaboration to improve AI systems.

Through its collective engineering efforts with industry and academia it continually measures and improves the accuracy, safety, speed and efficiency of AI technologies, including tiny devices.

**Benchmarking**

Benchmarks provide consistent measurements of accuracy, speed, and efficiency. Consistent measurements enable engineers to design reliable products and services, and enable researchers to compare innovations and choose the best ideas to drive the solutions of tomorrow.

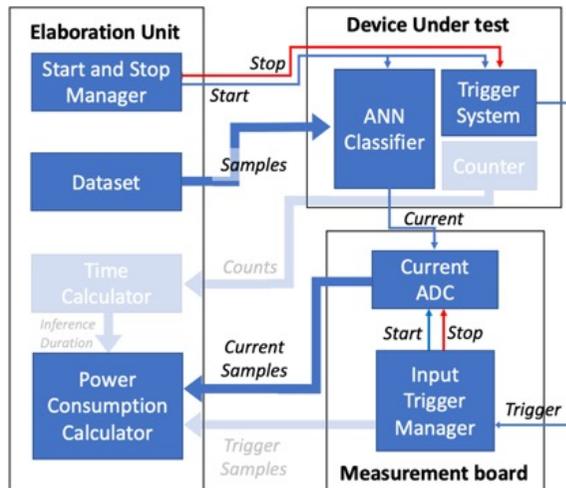
**Datasets**

Datasets are the raw materials for all of machine learning. Models are only as good as the data they are trained on. Academics and entrepreneurs in particular depend on public datasets to create new technologies and new companies.

**Best Practices**

Best Practices empower researchers and engineers to more easily exchange models, reproduce experiments, and build applications that leverages machine learning. Improving best practices accelerates progress in, and grows the market for, machine learning.

# Embedded AI – MLCommons method

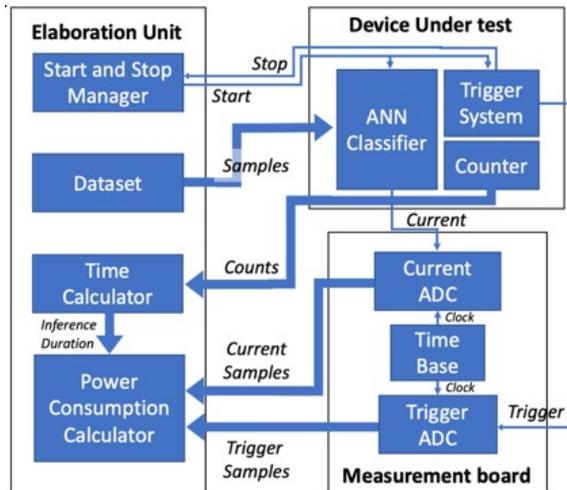


- The **DUT** hosting (i) a *Classifier* (an artificial neural network ANN) that executes N inferences in a certain inference time, (ii) a *Counter* for measuring the inference time, and (iii) a *General-Purpose Input-Output* transmitting a trigger signal to the measurement board.
- The **measurement board** hosting (i) an Ammeter that measures DUT current consumption, and (ii) a timestamp manager that receives measurement events from DUT
- The **elaboration unit** (a PC) hosting (i) datasets and ANNs used by the DUT to run inferences, and (ii) a measure program that collects the data from DUT and measurement board



**Problem:** between cycles are present some time window where inferences are not running. These can produce underestimation of power consumption.

# Embedded AI – Improved method



There are two main changes:

- The trigger is not a simple pulse, but it is a reference signal that allows to segment the inference phase.
- The ammeter returns a vector with the current samples measured over all the inference run
- The trigger reference signal and the current consumption are sampled with the same time base



Benchmarking procedure measures the average inference time and power consumption over N classifications inference cycles.

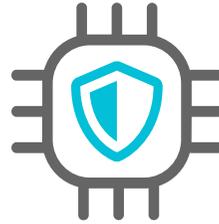
Each cycle is characterized by two phases:

- *pre-inference*, where the DUT prepares data into its memory to be inferred by the ANN model
- *Inference*, where data are effectively processed by the ANN running on the DUT.

# Embedded AI - Comparison

MLCommons Method	Proposed Method
Timing performance assessed as mean	Timing performance assessed as mean time on N inference cycles
Energy performance assessed as mean power consumption on a measure window that cover N inference cycles	Energy performance assessed as mean power consumption on N measure windows
The two measures are made in <u>different</u> time	The two measures are made in <u>same</u> time
The uncertainty can be assessed only on the timing performance	The uncertainty can be assessed on both measures

# Cyber-physical Attacks

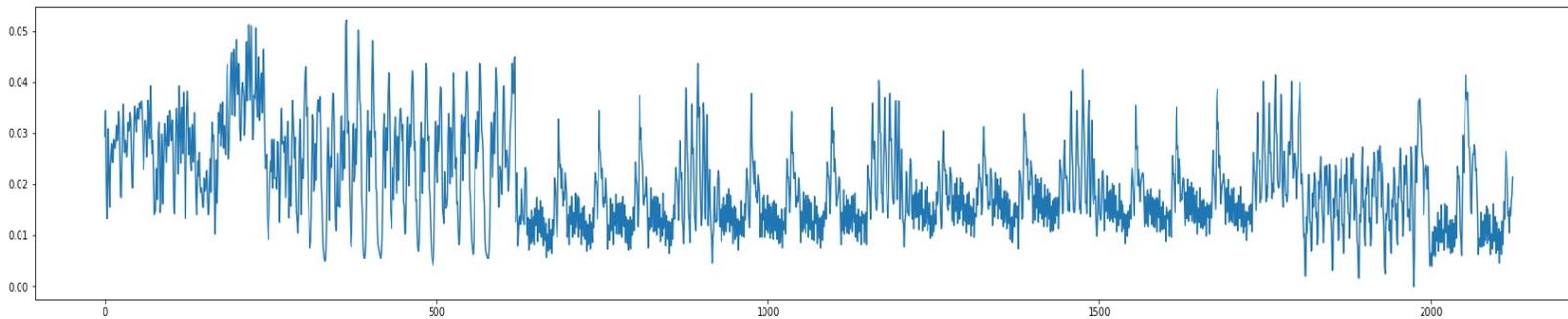
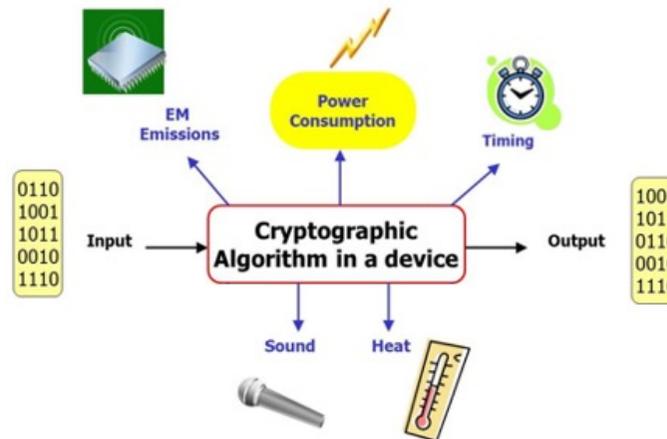


A **Secure Element** is a tamper-resistant platform (typically a one chip secure microcontroller) capable of securely hosting applications and their confidential and cryptographic data (for example cryptographic keys) in accordance with the rules and security requirements set by well-identified trusted authorities

An **attack** is an information security threat that involves an attempt to obtain, alter, destroy, remove, implant or reveal information without authorized access or permission

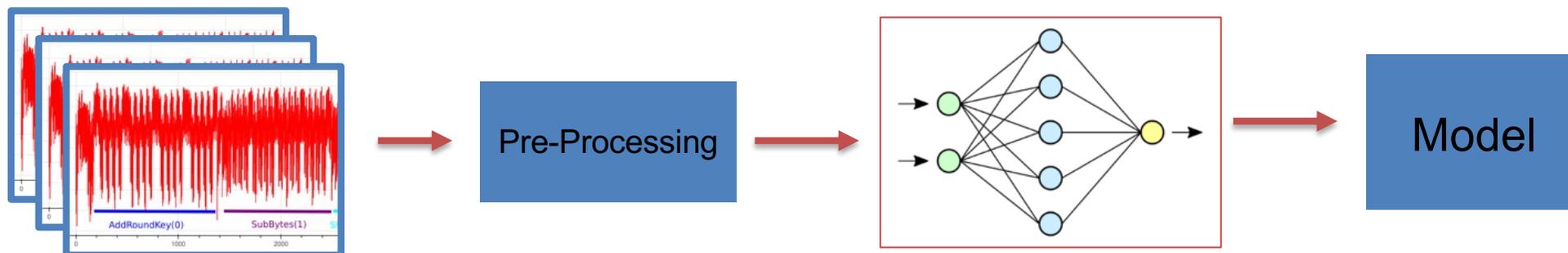
# Side-Channel Attacks

A **Side-Channel Attack** is a non-invasive attack aimed at extracting information that a particular system can exhibit

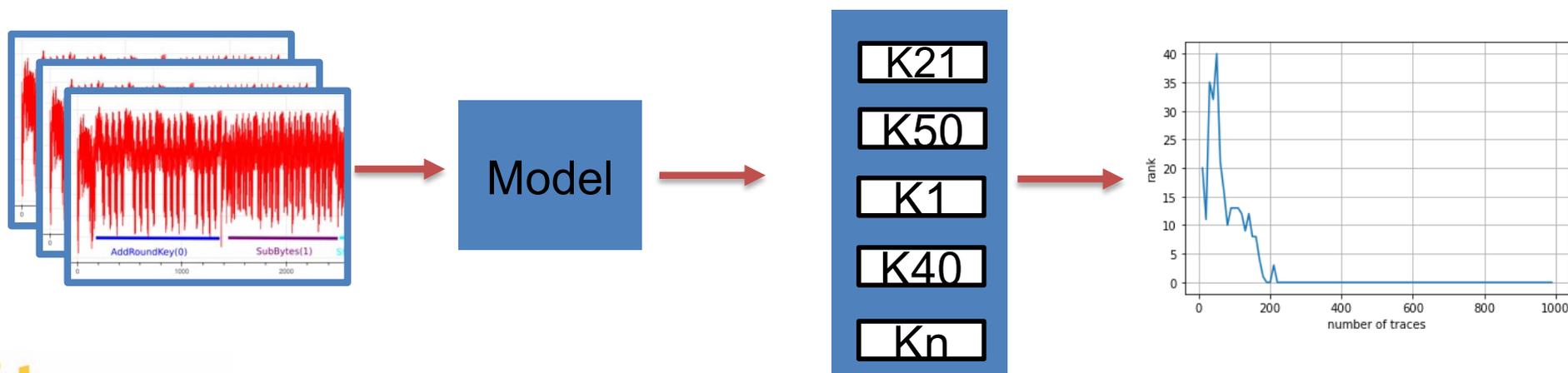


# Side-Channel Attacks – ML Approach

Traces are pre-processed and used to Train the attack model



The model is used to attack the device and a rank was estimated



# Products

[P1]	<i>P. Arpaia, F. Caputo, A. Cioffi, A. Esposito, F. Isgrò, <b>Uncertainty analysis in cryptographic key recovery for machine learning-based power measurements attacks</b>, IEEE Transactions for Instrumentation and Measurements (submitted), 2022</i>
[P2]	<i>IEEE International Conference On Metrology for eXtended Reality, Artificial Intelligence and Neural Engineering in Milan, presenting a demo about <b>Side-Channel Attacks using Machine Learning models</b>, 2023</i>
[P3]	<i>P.Arpaia, F.Caputo, A.Cioffi, A.Esposito, <b>The role of metrology in the cyber-security of embedded devices</b>, Acta IMEKO, 2023</i>
[P4]	<i>P.Arpaia, L.Capobianco, F.Caputo, A.Cioffi, A.Esposito, F. Isgrò, N. Moccaldi, D. Pau, D. Siorpaes, E. Toscano, <b>Accurate Energy Measurements for TinyML Workloads</b>, TinyML Summit, 2024</i>
[P5]	<i>P.Arpaia, L.Capobianco, F.Caputo, A.Cioffi, A.Esposito, F. Isgrò, N. Moccaldi, D. Pau, D. Siorpaes, E. Toscano, <b>Accurate Energy Measurements for TinyML Workloads</b>, IEEE MetroXRINE, St.Alban 2024</i>
[P6]	<i>P.Arpaia, L.Capobianco, F.Caputo, A.Cioffi, A.Esposito, F. Isgrò, N. Moccaldi, D. Pau, D. Siorpaes, E. Toscano, <b>Toward a standardized assessment of microcontroller performance in embedded AI</b>, 2025</i>

# Future Activities

- Research on other types of attacks like side-channels that can be measured
- Build of a dataset of cyber-physical attacks like Side-Channel or Fault attacks
- Build a neural model that can predict such attacks from a real time monitoring
- Embed the model and optimize it to work on edge device to build a secure smart network